

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1726	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3)same(compar\$6 or match\$4 or correlat\$6)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:17
L2	387	1 same(measur\$6 or calculat\$4 or comput\$6)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:18
L3	167	2 same(model\$4 or referenc\$4)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:18
L4	54	3 same(sensor\$2 or camera\$2 or scan\$4 or detect\$4)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:19
S1	5735	(artifact\$4 or nois\$4 or distort\$4)same(filter\$3)same(decod\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:26
S2	200	S1 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:43
S3	7388	(artifact\$4 or nois\$4 or distort\$4)same(decod\$3 or cod\$4)same(imag\$3)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:42
S4	820	(artifact\$4 or nois\$4 or distort\$4)same(decod\$3 or cod\$4)same(filter\$3 near10 imag\$3)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:42
S5	144	S4 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:51
S6	325	S4 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4 or block\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:48
S7	15	S6 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:51
S8	142	S4 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:48
S9	7	S8 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:48
S10	1	"6041145".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49
S11	1	"5949916".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49
S12	1	"5818964".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49
S13	1	"5802218".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49

S14	4490	(artifact\$4 or nois\$4 or distort\$4)same(filter\$3 near10(cod\$4 or decod\$3))	US-PGPUB; USPAT	OR	ON	2005/09/30 15:50
S15	195	S14 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:53
S16	9	S15 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 17:33
S17	124	S14 same(horizontal\$3 or vertical\$3)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:53
S18	4	S17 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:53
S19	1	"6178205".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S20	1	"5621468".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S21	1	"5570197".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S22	1	"5512956".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S23	1	"5502510".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S24	1	"5493456".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S25	1	"4991119".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S26	1	"4907082".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S27	1	"5819035".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S28	1	"5374995".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S29	1	"6178205".PN.	USPAT; USOCR	OR	ON	2005/09/30 17:36
S30	1	"5621468".PN.	USPAT; USOCR	OR	ON	2005/09/30 17:37
S31	1	"5570197".PN.	USPAT; USOCR	OR	ON	2005/09/30 17:37
S32	9064	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3 or align\$6 or measur\$6)same(compar\$6 or match\$4 or correlat\$6)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:16
S33	2742	S32 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:42

S34	726	S33 same(assembl\$4 or combin\$6 or merg\$6 or compos\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:37
S35	16884	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3 or align\$6 or measur\$6)same(scan\$4 or read\$4 or captur\$4 or detect\$4)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:36
S36	4136	S35 same(compar\$6 or match\$4 or correlat\$6 or similar\$4)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:37
S37	1180	S36 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:37
S38	356	S37 same(assembl\$4 or combin\$6 or merg\$6 or compos\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:38
S39	444	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3 near10 measur\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:41
S40	106	S39 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:49
S41	29	S39 same(compar\$6 or correlat\$4 or match\$4) near10(measur\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:49
S42	232	S37 same(compar\$6 or correlat\$4 or match\$4) near10(measur\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 16:04
S43	232	S42 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:50
S44	27	S43 same(auto\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:50
S45	61	S37 same(compar\$6 or correlat\$4 or match\$4) near10(measur\$6 near10(3D\$1 or 3-D\$1 or three-dimension\$4 or three adj2 dimension\$4))	US-PGPUB; USPAT	OR	ON	2005/10/20 13:16
S46	1	"5917937".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:16
S47	1	"5719954".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:18
S48	1	"5582173".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:19
S49	1	"5555352".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:19
S50	1	"5887083".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:20
S51	1	"5845006".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:21
S52	1	"5692061".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:21

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	(automat\$4 and assess\$4 and measur\$6 and assembl\$4 and three-dimension\$4).clm.	US-PGPUB	OR	ON	2005/10/20 15:48
L2	10	(automat\$4 and assess\$4 and measur\$6 and assembl\$4 and collect\$4).clm.	US-PGPUB	OR	ON	2005/10/20 15:48


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Key: IEEE JNL = IEEE Journal or Magazine, IEEE JNL = IEEE Journal or Magazine, IEEE CNF = IEEE Conference, IEEE CNF = IEEE Conference, IEEE STD = IEEE Standard

1. **Bayesian assembly of 3D axially symmetric shapes from fragments**
Willis, A.R.; Cooper, D.B.;
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2. **Something to smile about: 3D graphics are revolutionizing oral health care**
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3. **3D computer graphics based interface to real microscopic worlds for μ -robot telemanipulation and position control**
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4. **Test strategies for a 3-D stack multichip module space flight computer**
Sasidhar, K.; Alkalai, L.; Chatterjee, A.;
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5. **Improvement of metric accuracy of digital 3D models through digital photogrammetry. A case study: Donatello's Maddalena**
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6. **Detection of continuous symmetries in 3D objects from sparse measurements through probabilistic neural networks**
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7. **Object-based 3D X-ray image reconstruction**
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9. **Experiments in 3D measurements by using single camera and accurate motion**
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11. **Probabilistic octree modeling of a 3D dynamic environment**

Payeur, P.; Hebert, P.; Laurendeau, D.; Gosselin, C.M.;
Robotics and Automation, 1997. Proceedings., 1997 IEEE International Conference on
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12. **Use of reduced 3D hexahedral edge elements for 2D TE waveguides and vector potential problems**

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13. **Distributed virtual environments**

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14. **Video representation with three-dimensional entities**

Martins, F.C.M.; Moura, J.M.F.;
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15. **VizSim technology helps find oil faster**

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16. **Estuarine flows measured from an aircraft**

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21. A computer-assisted range image registration system for nuclear waste cleanup

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